

Notice of References Cited	Application/Control No. 10/575,767	Applicant(s)/Patent Under Reexamination LIOR ET AL.	
	Examiner Sophia S. Chen	Art Unit 2852	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,933,694	08-1999	Yamashita et al.	399/307(X)
*	B	US-5,987,284	11-1999	Lewis, Richard B.	399/249
*	C	US-6,002,907	12-1999	Berkes, John S.	399/307
*	D	US-6,078,776	06-2000	Okamoto et al.	399/308
*	E	US-6,356,728 B1	03-2002	Watanabe, Toshimi	399/251(X)
*	F	US-2002/0159801 A1	10-2002	Nakashima et al.	399/307
*	G	US-7,031,648 B2	04-2006	Takashi et al.	399/307
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2002-287530 A	10-2002	Japan	Ida et al.	-----/-----
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.